Notic of References Cited				10/088,494	10/088,494		SHIMIZU ET AL.	
				Examiner	Examiner		Art Unit	
				Deborah Yee	Deborah Yee		Page 1 of 1	
			***************************************	U.S. PATENT DOCUMENT	rs			
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY		Name		Classification	
	Α	US-						
	В	US-					•	
	С	US-						
	D	US-						
	E	US-						
	F	US-						
	G	US-						
	Н	US-				:		
	1	US-						
	J	US-		1				
	к	US-						
	L	US-						
	М	US-			-			
				REIGN PATENT DOCUM	ENTS			
*		Document Number Country Code-Number-Kind Code	MM-YYYY	Country	Name		Classification	
	N							
	0							
	Р							
	α							
	R						,	
	Ø							
	Т							
				NON-PATENT DOCUMEN				
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	٧			-				
	w							
	,,							

Application/Control No.

Applicant(s)/Patent Under

Reexamination

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.